





TRSF3222E SLLS823A - JULY 2007 - REVISED AUGUST 2021

## 3-V to 5.5-V Multichannel RS-232 Line Driver and Receiver with ±15-kV ESD Protection

#### 1 Features

- ESD Protection for RS-232 bus pins
  - ±15-kV Human-body model (HBM)
  - ±8-kV IEC 61000-4-2, Contact discharge
  - ±15-kV IEC 61000-4-2, Air-gap discharge
- Meets or exceeds the requirements of TIA/ EIA-232-F and ITU v.28 standards
- Operates with 3-V to 5.5-V V<sub>CC</sub> supply
- Operates up to 1000 kbit/s
- Two drivers and two receivers
- Low standby current . . . 1 µA Typ
- External capacitors . . . 4 × 0.1 µF
- Accepts 5-V logic input with 3.3-V supply

## 2 Applications

- **Industrial PCs**
- Wired networking
- Data center and networking equipment
- **Notebooks**
- Hand-held equipment

## 3 Description

The TRSF3222E consists of two line drivers, two line receivers, and a dual charge-pump circuit with ±15-kV ESD protection pin to pin (serial-port connection pins, including GND).

The TRSF3222E meets the requirements of TIA/ EIA-232-F and provides the electrical interface between an asynchronous communication controller and the serial-port connector. The charge pump and four small external capacitors allow operation from a single 3-V to 5.5-V supply. The TRSF3222E operates at typical data signaling rates up to

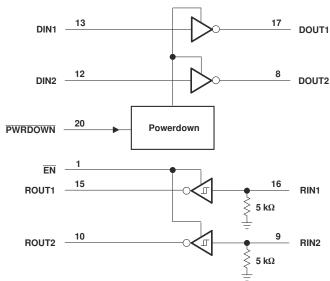
1000 kbit/s and is an improved drop-in replacement for industry-popular '3222 two-driver, two-receiver functions.

The TRSF3222E can be placed in the power-down mode by setting the power-down (PWRDOWN) input low, which draws only 1 µA from the power supply. When the device is powered down, the receivers remain active while the drivers are placed in the high-impedance state. Also, during power down, the onboard charge pump is disabled; V+ is lowered to V<sub>CC</sub>, and V- is raised toward GND. Receiver outputs also can be placed in the high-impedance state by setting enable ( EN) high.

#### **Device Information**

PART NUMBER	PACKAGE <sup>(1)</sup>	BODY SIZE (NOM)	
	DB (SSOP) (20)	10.2 mm x 5.30 mm	
TRSF3222E	DW (SOIC) (20)	15.4 mm x 7.50 mm	
	PW (TSSOP) (20)	7.80 mm v 4.40 mm	

(1) For all available packages, see the orderable addendum at the end of the data sheet.



Pin numbers shown are for the DB, DW, and PW packages.

### Logic Diagram (Positive Logic)



## **Table of Contents**

1 Features	1	7 Parameter Measurement Information	8
2 Applications	1	8 Detailed Description	10
3 Description		8.1 Functional Block Diagram	10
4 Revision History	2	8.2 Device Functional Modes	10
5 Pin Configuration and Functions	3	9 Application and Implementation	11
6 Specifications	4	9.1 Application Information	<mark>11</mark>
6.1 Absolute Maximum Ratings	4	9.2 Typical Application	11
6.2 ESD Ratings	4	10 Device and Documentation Support	12
6.3 ESD Ratings - IEC Specifications	4	10.1 Receiving Notification of Documentation Upon	dates12
6.4 Recommended Operating Conditions	<mark>5</mark>	10.2 Support Resources	12
6.5 Thermal Information	<mark>5</mark>	10.3 Trademarks	12
6.6 Electrical Characteristics	<mark>5</mark>	10.4 Electrostatic Discharge Caution	12
6.7 Electrical Characteristics: Driver	6	10.5 Glossary	12
6.8 Switching Characteristics: Driver	6	11 Mechanical, Packaging, and Orderable	
6.9 Electrical Characteristics: Receiver	7	Information	12
6.10 Switching Characteristics: Receiver	<mark>7</mark>		

## **4 Revision History**

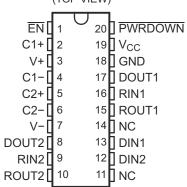
NOTE: Page numbers for previous revisions may differ from page numbers in the current version.

С	hanges from Revision * (July 2007) to Revision A (August 2021)	Page
•	Updated the list of Applications	1
•	Deleted the Ordering Information table	
•	Added the Device Information table, the Pin Configuration and Functions, the Detailed Description sect	ion,
	the Application and Implementation section	
•	Deleted the Package thermal impedance from the Absolute Maximum Ratings	4
•	Added the ESD Ratings table	4
•	Added the ESD Ratings - IEC Specifications table	4
•	Added the Thermal Information table	5
	Changed the value of R <sub>BJA</sub> for PW package (previously in the Absolute Maximum Ratings table), and a	
	additional thermal parameters for all packages in the <i>Thermal Information</i> table	



## **5 Pin Configuration and Functions**

DB, DW, OR PW PACKAGE (TOP VIEW)



NC - No internal connection

**Table 5-1. Pin Functions** 

Р	IN	1/0	DECODINE
NAME	NO.	I/O	DESCRIPTION
C1+	2	_	Charge pump capacitor pin
C1-	4	_	Charge pump capacitor pin
C2+	5	_	Charge pump capacitor pin
C2-	6	_	Charge pump capacitor pin
DIN1	13	I	Driver logic input
DIN2	12	I	Driver logic input
DOUT1	17	0	RS-232 driver output
DOUT2	8	0	RS-232 driver output
ĒN	1	I	Receiver enable, active low
GND	18	_	Ground
NC	11,14	_	No internal connection
PWRDOWN	20	I	Driver disable, active low
RIN1	16	I	RS-232 receiver input
RIN2	9	I	RS-232 receiver input
ROUT1	15	0	Receiver logic output
ROUT2	10	0	Receiver logic output
V <sub>CC</sub>	19	_	Power Supply
V+	3	_	Charge pump capacitor pin
V-	7	_	Charge pump capacitor pin



## **6 Specifications**

## 6.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted) (1)

			MIN	MAX	UNIT
V <sub>CC</sub>	Supply voltage range <sup>(2)</sup>	Supply voltage range <sup>(2)</sup>		6	V
V+	Positive-output supply voltage range <sup>(2)</sup>		-0.3	7	V
V-	Negative-output supply voltage range <sup>(2)</sup>	Negative-output supply voltage range <sup>(2)</sup>		-7	V
V+ – V–	Supply voltage difference <sup>(2)</sup>			13	V
.,	Input voltage range	Driver ( EN, PWRDOWN)	-0.3	6	V
V <sub>I</sub>		Receiver	-25	25	V
V	Output valtage renge	Driver	-13.2	13.2	V
Vo	Output voltage range Receiver		-0.3	V <sub>CC</sub> + 0.3	V
TJ	Operating virtual junction temperature			150	°C
T <sub>stg</sub>	Storage temperature range		-65	150	°C

<sup>(1)</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

## 6.2 ESD Ratings

				VALUE	UNIT
V <sub>(ESD)</sub>		Human-body model (HBM), per ANSI/	All pins except RIN1, RIN2, DOUT1 and DOUT2 pins	±3000	
	Electrostatic discharge	Electrostatic ESDA/JEDEC JS-001 <sup>(1)</sup>	RIN1, RIN2, DIN1 and DOUT2 pins to GND	±15,000	V
		Charged device model (CDM), per ANSI/ ESDA/JEDEC JS-002 <sup>(2)</sup>		±1500	

- (1) JEDEC document JEP155 states that 500-V HBM allows safe manufacturing with a standard ESD control process.
- (2) JEDEC document JEP157 states that 250-V CDM allows safe manufacturing with a standard ESD control process.

## 6.3 ESD Ratings - IEC Specifications

					VALUE	UNIT
V		etrostatic IEC 61000-4-2 Contact Discharge (1)	Pins RIN1, RIN2, DOUT1, DOUT2 only	±8,000	V	
\ \ \ (E	<sup>(SD)</sup> disc	harge	IEC 61000-4-2 Air Discharge (1)		±15,000	<b>'</b>

(1) For PW package only, a minimum of 1-µF capacitor is required between V<sub>CC</sub> and GND to meet the specified IEC 61000-4-2 rating.

Submit Document Feedback

<sup>(2)</sup> All voltages are with respect to network GND.



## **6.4 Recommended Operating Conditions**

See Figure 9-1 and (1)

				MIN	NOM	MAX	UNIT
	Supply voltage		V <sub>CC</sub> = 3.3 V	3	3.3	3.6	V
			V <sub>CC</sub> = 5 V	4.5	5	5.5	v
V <sub>IH</sub>	Driver and control high-level input voltage	DIN, EN, PWRDOWN	V <sub>CC</sub> = 3.3 V	2			V
VIH	Driver and control high-level input voltage	grand control night-lever input voltage	V <sub>CC</sub> = 5 V	2.4			v
V <sub>IL</sub>	Driver and control low-level input voltage	DIN, EN, PWRDOWN				0.8	V
VI	Driver and control input voltage	DIN, EN, PWRDOWN		0		5.5	V
VI	Receiver input voltage			-25		25	V
т			TRSF3222EC	0		70	°C
T <sub>A</sub>	Operating free-air temperature	TRSF3222EI	-40		85		

<sup>(1)</sup> Test conditions are C1–C4 = 0.1  $\mu$ F at V<sub>CC</sub> = 3.3 V  $\pm$  0.3 V; C1 = 0.047  $\mu$ F, C2–C4 = 0.33  $\mu$ F at V<sub>CC</sub> = 5 V  $\pm$  0.5 V.

#### 6.5 Thermal Information

			TRSF3222E			
	THERMAL METRIC(1)	DB (SSOP)	DW (SOIC)	PW (TSSOP)	UNIT	
		20 Pins	20 Pins	20 Pins		
R <sub>θJA</sub>	Junction-to-ambient thermal resistance	70	58	94.1	°C/W	
R <sub>θJB</sub>	Junction-to-board thermal resistance	33.6	30.0	35.2	°C/W	
Ψ ЈТ	Junction-to-top characterization parameter	36.4	29.6	45.5	°C/W	
Ψ ЈВ	Junction-to-board characterization parameter	4.8	7.7	3.1	°C/W	
R <sub>θJC(bot)</sub>	Junction-to-case (bottom) thermal resistance	35.9	29.3	45.1	°C/W	

For more information about traditional and new thermal metrics, see the Semiconductor and IC package thermal metrics application report.

#### 6.6 Electrical Characteristics

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (see Figure 9-1)

	0 11 0	·			,
	PARAMETER	TEST CONDITIONS <sup>(2)</sup>	MIN TYP <sup>(1)</sup>	MAX	UNIT
I	Input leakage current ( EN, PWRDOWN)		±0.01	±1	μA
	'''	No load, PWRDOWN at V <sub>CC</sub>	0.3	1	mA
IC	Supply current (powered off)	No load, PWRDOWN at GND	1	10	μA

<sup>(1)</sup> All typical values are at  $V_{CC}$  = 3.3 V or  $V_{CC}$  = 5 V, and  $T_A$  = 25°C. (2) Test conditions are C1–C4 = 0.1  $\mu$ F at  $V_{CC}$  = 3.3 V  $\pm$  0.3 V; C1 = 0.047  $\mu$ F, C2–C4 = 0.33  $\mu$ F at  $V_{CC}$  = 5 V  $\pm$  0.5 V.



#### 6.7 Electrical Characteristics: Driver

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (see Figure 9-1)

PARAMETER		TEST CONDITIONS(3)		MIN	TYP <sup>(1)</sup>	MAX	UNIT
V <sub>OH</sub>	High-level output voltage	DOUT at $R_L = 3 \text{ k}\Omega$ to GND,	DIN = GND	5	5.4		V
V <sub>OL</sub>	Low-level output voltage	DOUT at $R_L = 3 \text{ k}\Omega$ to GND,	DIN = V <sub>CC</sub>	<b>–</b> 5	-5.4		V
I <sub>IH</sub>	High-level input current	V <sub>I</sub> = V <sub>CC</sub>			±0.01	±1	μA
I <sub>IL</sub>	Low-level input current	V <sub>I</sub> at GND	V <sub>I</sub> at GND		±0.01	±1	μA
	Short-circuit output current <sup>(2)</sup>	V <sub>CC</sub> = 3.6 V	V <sub>O</sub> = 0 V		±35	±60	mA
Ios	Short-circuit output current	V <sub>CC</sub> = 5.5 V	V <sub>0</sub> = 0 V		133	100	ША
r <sub>o</sub>	Output resistance	V <sub>CC</sub> , V+, and V- = 0 V,	V <sub>O</sub> = ±2 V	300	10M		Ω
	Output lookogo gurrent	PWRDOWN = GND	V <sub>CC</sub> = 3 V to 3.6 V, V <sub>O</sub> = ±12 V			±25	
l <sub>OZ</sub>	Output leakage current	F WKDOWN - GND	$V_{CC} = 4.5 \text{ V to } 5.5 \text{ V},$ $V_{O} = \pm 10 \text{ V}$			±25	μA

- (1)
- All typical values are at  $V_{CC}$  = 3.3 V or  $V_{CC}$  = 5 V, and  $T_A$  = 25°C. Short-circuit durations should be controlled to prevent exceeding the device absolute power dissipation ratings, and not more than one output should be shorted at a time.
- Test conditions are C1–C4 = 0.1  $\mu$ F at  $V_{CC}$  = 3.3 V  $\pm$  0.3 V; C1 = 0.047  $\mu$ F, C2–C4 = 0.33  $\mu$ F at  $V_{CC}$  = 5 V  $\pm$  0.5 V.

## 6.8 Switching Characteristics: Driver

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (see Figure 9-1)

	PARAMETER		TEST CONDITIONS <sup>(3)</sup>			TYP <sup>(1)</sup>	MAX	UNIT	
			C <sub>L</sub> = 1000 pF		250				
	Maximum data rate (See Figure 7-1)	- ,	C <sub>L</sub> = 250 pF,	V <sub>CC</sub> = 3 V to 4.5 V	1000			kbit/s	
	(Coorigator 1)	one boot emicriming	C <sub>L</sub> = 1000 pF,	V <sub>CC</sub> = 4.5 V to 5.5 V	1000				
t <sub>sk(p)</sub>	Pulse skew <sup>(2)</sup>	C <sub>L</sub> = 150 pF to 2500 pF,	$R_L = 3 k\Omega \text{ to } 7 k\Omega$	See Figure 7-2		300		ns	
	Slew rate	Slew rate.	$R_L = 7 k\Omega$ ,	C <sub>L</sub> = 150 pF to 1000 pl	F	8		90	
SR(tr)	transition region	on region	C <sub>L</sub> = 1000 pF		12		60	V/µs	
	(see Figure 7-1)	(see Figure 7-1) $R_L = 3 \text{ k}\Omega$		C <sub>L</sub> = 150 pF to 250 pF		24		150	

- All typical values are at  $V_{CC}$  = 3.3 V or  $V_{CC}$  = 5 V, and  $T_A$  = 25°C.
- (2)
- Pulse skew is defined as  $|t_{PLH}-t_{PHL}|$  of each channel of the same device. Test conditions are C1–C4 = 0.1  $\mu$ F at  $V_{CC}$  = 3.3 V  $\pm$  0.3 V; C1 = 0.047  $\mu$ F, C2–C4 = 0.33  $\mu$ F at  $V_{CC}$  = 5 V  $\pm$  0.5 V.

Submit Document Feedback



#### 6.9 Electrical Characteristics: Receiver

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (see Figure 9-1)

	PARAMETER	TEST CONDITIONS(2)	MIN	TYP <sup>(1)</sup>	MAX	UNIT	
V <sub>OH</sub>	High-level output voltage	I <sub>OH</sub> = -1 mA	V <sub>CC</sub> - 0.6	V <sub>CC</sub> - 0.1		V	
V <sub>OL</sub>	Low-level output voltage	I <sub>OL</sub> = 1.6 mA			0.4	V	
V <sub>IT+</sub> Po	Positive-going input threshold voltage	V <sub>CC</sub> = 3.3 V		1.5	2.4	V	
	Positive-going input tineshold voltage	V <sub>CC</sub> = 5 V		1.8	2.4	v	
\/	Negative-going input threshold voltage	V <sub>CC</sub> = 3.3 V	0.6	1.2		V	
$V_{IT-}$	Negative-going input the shold voltage	V <sub>CC</sub> = 5 V	0.8	1.5		V	
V <sub>hys</sub>	Input hysteresis (V <sub>IT+</sub> – V <sub>IT-</sub> )			0.3		V	
I <sub>OZ</sub>	Output leakage current	EN = 1		±0.05	±10	μΑ	
r <sub>i</sub>	Input resistance	$V_1 = \pm 3 \text{ V to } \pm 25 \text{ V}$	3	5	7	kΩ	

All typical values are at  $V_{CC}$  = 3.3 V or  $V_{CC}$  = 5 V, and  $T_A$  = 25°C.

## **6.10 Switching Characteristics: Receiver**

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

	PARAMETER	TEST CONDITIONS(3)	TYP <sup>(1)</sup>	UNIT
t <sub>PLH</sub>	Propagation delay time, low- to high-level output	C <sub>L</sub> = 150 pF, See Figure 7-3	300	ns
t <sub>PHL</sub>	Propagation delay time, high- to low-level output	C <sub>L</sub> = 150 pF, See Figure 7-3	300	ns
t <sub>en</sub>	Output enable time	$C_L$ = 150 pF, $R_L$ = 3 k $\Omega$ , See Figure 7-4	200	ns
t <sub>dis</sub>	Output disable time	$C_L$ = 150 pF, $R_L$ = 3 k $\Omega$ , See Figure 7-4	200	ns
t <sub>sk(p)</sub>	Pulse skew <sup>(2)</sup>	See Figure 7-3	300	ns

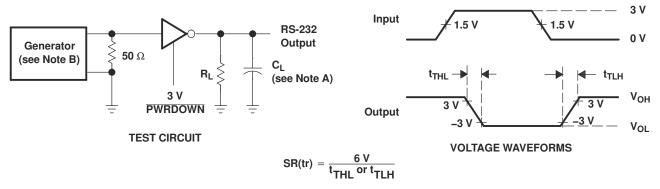
All typical values are at  $V_{CC}$  = 3.3 V or  $V_{CC}$  = 5 V, and  $T_A$  = 25°C.

Test conditions are C1–C4 = 0.1  $\mu$ F at  $V_{CC}$  = 3.3  $V \pm 0.3$  V; C1 = 0.047  $\mu$ F, C2–C4 = 0.33  $\mu$ F at  $V_{CC}$  = 5  $V \pm 0.5$  V.

Pulse skew is defined as  $|t_{PLH}-t_{PHL}|$  of each channel of the same device. Test conditions are C1–C4 = 0.1  $\mu$ F at V<sub>CC</sub> = 3.3 V  $\pm$  0.3 V; C1 = 0.047  $\mu$ F, C2–C4 = 0.33  $\mu$ F at V<sub>CC</sub> = 5 V  $\pm$  0.5 V. (3)

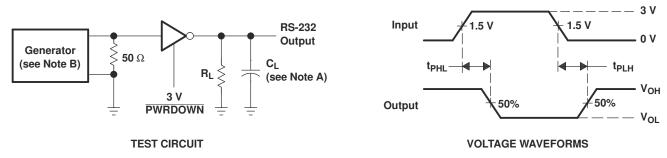


### 7 Parameter Measurement Information



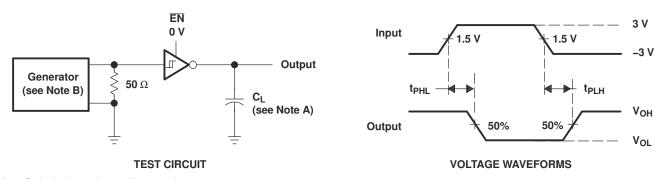
- A. C<sub>L</sub> includes probe and jig capacitance.
- B. The pulse generator has the following characteristics: PRR = 250 kbit/s,  $Z_0 = 50 \Omega$ , 50% duty cycle,  $t_r \le 10$  ns,  $t_f \le 10$  ns.

Figure 7-1. Driver Slew Rate



- C<sub>L</sub> includes probe and jig capacitance.
- B. The pulse generator has the following characteristics: PRR = 250 kbit/s,  $Z_O = 50 \Omega$ , 50% duty cycle,  $t_r \le 10$  ns.  $t_f \le 10$  ns.

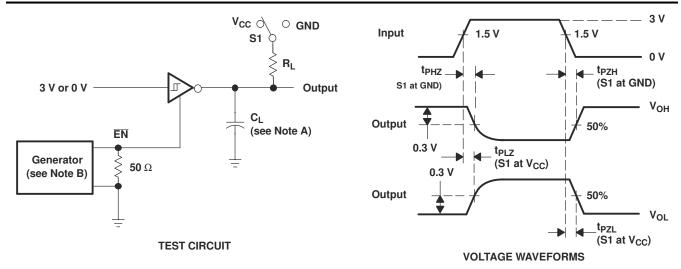
Figure 7-2. Driver Pulse Skew



- C<sub>L</sub> includes probe and jig capacitance.
- B. The pulse generator has the following characteristics:  $Z_0$  = 50  $\Omega$ , 50% duty cycle,  $t_r \le 10$  ns,  $t_f \le 10$  ns.

Figure 7-3. Receiver Propagation Delay Times





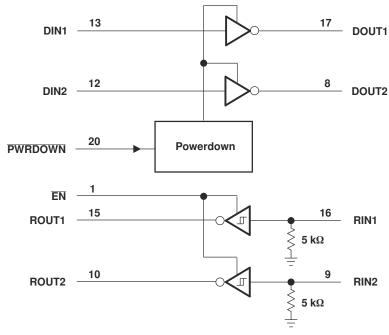
- A. C<sub>L</sub> includes probe and jig capacitance.
- B. The pulse generator has the following characteristics:  $Z_0$  = 50  $\Omega$ , 50% duty cycle,  $t_r \le 10$  ns,  $t_f \le 10$  ns.

Figure 7-4. Receiver Enable and Disable Times



## **8 Detailed Description**

## 8.1 Functional Block Diagram



A. Pin numbers shown are for the DB, DW, and PW packages.

Figure 8-1. Logic Diagram (Positive Logic)

### 8.2 Device Functional Modes

Table 8-1. Function Table: Each Driver

INF	PUTS <sup>(1)</sup>	OUTPUT
DIN	PWRDOWN	DOUT
X	L	Z
L	Н	Н
Н	Н	L

(1) H = high level, L = low level, X = irrelevant, Z = high impedance

Table 8-2. Function Table: Each Receiver

INPUTS(1)		OUTPUT				
RIN	EN	ROUT				
L	L	Н				
Н	L	L				
Х	Н	z				
Open	L	Н				

(1) H = high level, L = low level, X = irrelevant, Z = high impedance (off),

Open = input disconnected or connected driver off

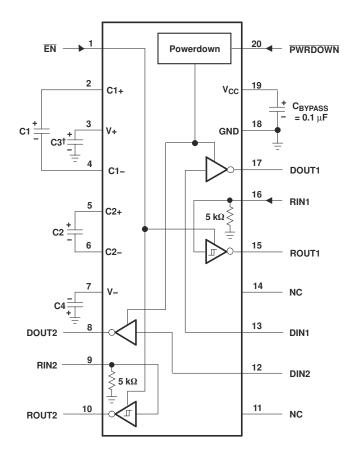
## 9 Application and Implementation

#### Note

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes, as well as validating and testing their design implementation to confirm system functionality.

## 9.1 Application Information

## 9.2 Typical Application



 $<sup>^\</sup>dagger$  C3 can be connected to  $V_{\mbox{\footnotesize CC}}$  or GND.

NOTES: A. Resistor values shown are nominal.

#### V<sub>CC</sub> vs CAPACITOR VALUES

V <sub>CC</sub>	C1	C2, C3, and C4			
3.3 V $\pm$ 0.3 V	<b>0.1</b> μ <b>F</b>	<b>0.1</b> μ <b>F</b>			
5 V $\pm$ 0.5 V	<b>0.047</b> μ <b>F</b>	<b>0.33</b> μF			
3 V to 5.5 V	<b>0.1</b> μ <b>F</b>	<b>0.47</b> μ <b>F</b>			

Figure 9-1. Typical Operating Circuit and Capacitor Values

B. NC - No internal connection

C. Nonpolarized ceramic capacitors are acceptable. If polarized tantalum or electrolytic capacitors are used, they should be connected as shown.



## 10 Device and Documentation Support

TI offers an extensive line of development tools. Tools and software to evaluate the performance of the device, generate code, and develop solutions are listed below.

### 10.1 Receiving Notification of Documentation Updates

To receive notification of documentation updates, navigate to the device product folder on ti.com. Click on *Subscribe to updates* to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

#### 10.2 Support Resources

TI E2E<sup>™</sup> support forums are an engineer's go-to source for fast, verified answers and design help — straight from the experts. Search existing answers or ask your own question to get the quick design help you need.

Linked content is provided "AS IS" by the respective contributors. They do not constitute TI specifications and do not necessarily reflect TI's views; see TI's Terms of Use.

#### 10.3 Trademarks

TI E2E™ is a trademark of Texas Instruments.

All trademarks are the property of their respective owners.

## 10.4 Electrostatic Discharge Caution



This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

### 10.5 Glossary

TI Glossary

This glossary lists and explains terms, acronyms, and definitions.

## 11 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

Submit Document Feedback

www.ti.com 26-Apr-2023

#### PACKAGING INFORMATION

Orderable Device	Status	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead finish/ Ball material	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
TRSF3222ECDB	NRND	SSOP	DB	20	70	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	0 to 70	RT22EC	
TRSF3222EIDWR	NRND	SOIC	DW	20	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	TRSF3222EI	
TRSF3222EIPWR	ACTIVE	TSSOP	PW	20	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	RT22EI	Samples

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

**OBSOLETE:** TI has discontinued the production of the device.

(2) RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

- (3) MSL, Peak Temp. The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.
- <sup>(4)</sup> There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.
- (6) Lead finish/Ball material Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

**Important Information and Disclaimer:** The information provided on this page represents TI's knowledge and belief as of the date that it is provided. TI bases its knowledge and belief on information provided by third parties, and makes no representation or warranty as to the accuracy of such information. Efforts are underway to better integrate information from third parties. TI has taken and continues to take reasonable steps to provide representative and accurate information but may not have conducted destructive testing or chemical analysis on incoming materials and chemicals. TI and TI suppliers consider certain information to be proprietary, and thus CAS numbers and other limited information may not be available for release.

In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.



## **PACKAGE OPTION ADDENDUM**

www.ti.com 26-Apr-2023

## **PACKAGE MATERIALS INFORMATION**

www.ti.com 28-Sep-2022

## TAPE AND REEL INFORMATION





A0	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

#### QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE

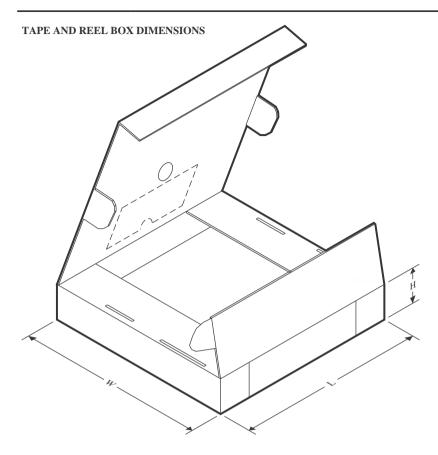


#### \*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
TRSF3222EIDWR	SOIC	DW	20	2000	330.0	24.4	10.8	13.3	2.7	12.0	24.0	Q1
TRSF3222EIPWR	TSSOP	PW	20	2000	330.0	16.4	6.95	7.0	1.4	8.0	16.0	Q1
TRSF3222EIPWR	TSSOP	PW	20	2000	330.0	16.4	6.95	7.1	1.6	8.0	16.0	Q1



www.ti.com 28-Sep-2022



### \*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
TRSF3222EIDWR	SOIC	DW	20	2000	367.0	367.0	45.0
TRSF3222EIPWR	TSSOP	PW	20	2000	356.0	356.0	35.0
TRSF3222EIPWR	TSSOP	PW	20	2000	356.0	356.0	35.0

## **PACKAGE MATERIALS INFORMATION**

www.ti.com 28-Sep-2022

## **TUBE**



#### \*All dimensions are nominal

Devi	се	Package Name	Package Type	Pins	SPQ	L (mm)	W (mm)	T (µm)	B (mm)
TRSF322	2ECDB	DB	SSOP	20	70	530	10.5	4000	4.1





#### NOTES:

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

  2. This drawing is subject to change without notice.

  3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.25 mm per side.
- 5. Reference JEDEC registration MO-153.





NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.





NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.



# PW (R-PDSO-G20)

## PLASTIC SMALL OUTLINE



NOTES:

- All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.C. Publication IPC-7351 is recommended for alternate design.
- D. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC-7525 for other stencil recommendations.
- E. Customers should contact their board fabrication site for solder mask tolerances between and around signal pads.







### NOTES:

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

  2. This drawing is subject to change without notice.

  3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.25 mm per side.
- 5. Reference JEDEC registration MO-150.





NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.





NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.





SOIC



#### NOTES:

- 1. All linear dimensions are in millimeters. Dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

  2. This drawing is subject to change without notice.

  3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.43 mm per side.
- 5. Reference JEDEC registration MS-013.



SOIC



NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



SOIC



NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.



## IMPORTANT NOTICE AND DISCLAIMER

TI PROVIDES TECHNICAL AND RELIABILITY DATA (INCLUDING DATA SHEETS), DESIGN RESOURCES (INCLUDING REFERENCE DESIGNS), APPLICATION OR OTHER DESIGN ADVICE, WEB TOOLS, SAFETY INFORMATION, AND OTHER RESOURCES "AS IS" AND WITH ALL FAULTS, AND DISCLAIMS ALL WARRANTIES, EXPRESS AND IMPLIED, INCLUDING WITHOUT LIMITATION ANY IMPLIED WARRANTIES OF MERCHANTABILITY, FITNESS FOR A PARTICULAR PURPOSE OR NON-INFRINGEMENT OF THIRD PARTY INTELLECTUAL PROPERTY RIGHTS.

These resources are intended for skilled developers designing with TI products. You are solely responsible for (1) selecting the appropriate TI products for your application, (2) designing, validating and testing your application, and (3) ensuring your application meets applicable standards, and any other safety, security, regulatory or other requirements.

These resources are subject to change without notice. TI grants you permission to use these resources only for development of an application that uses the TI products described in the resource. Other reproduction and display of these resources is prohibited. No license is granted to any other TI intellectual property right or to any third party intellectual property right. TI disclaims responsibility for, and you will fully indemnify TI and its representatives against, any claims, damages, costs, losses, and liabilities arising out of your use of these resources.

TI's products are provided subject to TI's Terms of Sale or other applicable terms available either on ti.com or provided in conjunction with such TI products. TI's provision of these resources does not expand or otherwise alter TI's applicable warranties or warranty disclaimers for TI products.

TI objects to and rejects any additional or different terms you may have proposed.

Mailing Address: Texas Instruments, Post Office Box 655303, Dallas, Texas 75265 Copyright © 2023, Texas Instruments Incorporated